Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/609,141	PLACKLE ET AL.	
Examiner	Art Unit	
Gopal C. Ray	2111	

SEARCHED					
Class	Subclass	Date	Examiner		
710	1,8,105,30 5,2,104,30 6	6/2/2005	GCR		
716	16,17	6/2/2005	GCR		
712	32,37,41	6/2/2005	GCR		
326	37-39	6/2/2005	GCR		
370	402,465	6/3/2005	GCR		
709	253	6/3/2005	GCR		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
WEST: USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB	6/2/2005	GCR
EAST: USPT	6/2/2005	GCR
NPL: IEEE Xplore	6/2/2005	GCR
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